



SiliconGo eMMC Product Family

eMMC5.1 Specification Compatibility

SGM8100C-S36BCG

SGM8100C-S36BDG

Datasheet

V1.0

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Revision History

| Revision No. | Date | History | Remark |
|--------------|------------|--------------------|--------|
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| 1.0 | 2021-11-15 | 1. Customer sample | Final |

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1 Introduction

1.1 General Description

SiliconGo e•MMC is an embedded storage solution designed in a BGA package form. The operation of e•MMC is a simple read and write to memory using e•MMC protocol v5.1 which is an industry standard.

The e•MMC consists of NAND flash and a MMC controller. 3.3V supply voltage is required for the NAND area (V_{CC}), whereas 1.8V or 3.3V dual supply voltage (V_{CC} or V_{CCQ}) is supported for MMC controller.

There are several advantages of e•MMC. It is easy to be used on the standard interface, which allows the easy and widely used integration with general CPU. Any revision or amendment of NAND is invisible to the host as the embedded e•MMC controller insulates NAND technology from the host. It means that the host can support the newest processing flash without updating its hardware or software.

SiliconGo e•MMC has high performance at a competitive-cost, high quality and low power consumption. e•MMC provides capacities from 4GB to 128GB.

1.2 Product List

| Capacity | Part Number | NAND Flash Type | Package Size | Package Type |
|----------|-----------------|-----------------|------------------|--------------|
| 64 GB | SGM8100C-S36BCG | 512Gb x1 | 11.5x13x1.0 (mm) | 153 FBGA |
| 128 GB | SGM8100C-S36BDG | 512Gb x2 | 11.5x13x1.0 (mm) | 153 FBGA |

1.3 Key Feature

- **e•MMC v5.1 compatible. Detail description is referenced by JEDEC Standard**
 - (Backward compatible to e•MMC v4.41/v4.5/v5.0)
- **Bus mode**
 - Data bus width: 1bit(default), 4bit and 8bit
 - Data transfer rate: up to 400MB/s (HS400) @ 200MHz DDR with 8bit bus width
 - MMC I/F Clock Frequency: 0~200MHz
 - MMC I/F Boot Frequency: 0~52MHz
- **Operating Voltage Range**
 - V_{CC} (NAND/Core): 2.7V ~ 3.6V
 - V_{CCQ} (CTRL/IO): 1.7V ~ 1.95V / 2.7V ~ 3.6V
- **Temperature**
 - Operation (-25°C ~ 85°C)
 - Storage without operation (-40°C ~ 85°C)

■ Supports Features

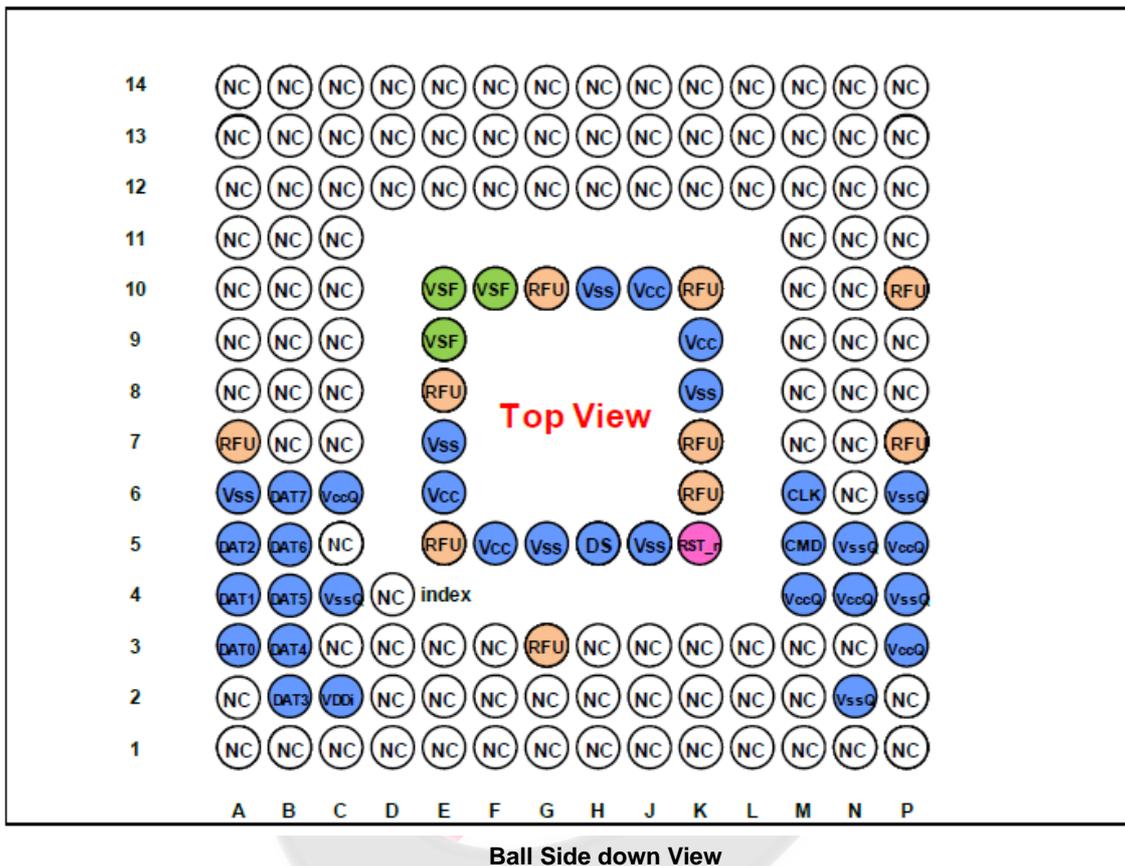
- HS400, HS200, DDR52, SDR52
- High Priority Interrupt (HPI)
- Background Operation, **BKOPS Control**
- Packed CMD, **Command Queuing**
- Cache, **Cache Flushing Report, Cache Barrier** (Optional)
- Partitioning, Partition types, RPMB, **RPMB Throughput Improve**
- Discard, Trim, Erase, Sanitize
- Write Protect, **Secure Write Protection** (Optional)
- Lock/Unlock
- Power Off Notification(PON), Sleep/Awake
- Enhance Reliable Write
- Boot feature, Boot partition
- Context IDs, Data Tag, Real Time Clock
- HW/SW Reset
- Configurable driver strength
- Field Firmware Update
- Secure Removal Type (Optional)
- Device Health Report (Optional)
- Production State Awareness (Optional)
- Data Strobe pin, **Enhanced Strobe** (Optional)
(Bold features are added in eMMC5.1)

■ Others

- This product is compliance with the RoHS directive.

2 Package Configurations

2.1 153-FBGA Ball Array View



| Ball No. | Name | Ball No. | Name | Ball No. | Name | Ball No. | Name |
|----------|------|----------|------|----------|-------|----------|------|
| A3 | DAT0 | C2 | VDDi | J5 | Vss | N4 | Vcca |
| A4 | DAT1 | C4 | Vssa | J10 | Vcc | N5 | Vssa |
| A5 | DAT2 | C6 | Vcca | K5 | RST_n | P3 | Vcca |
| A6 | Vss | E6 | Vcc | K8 | Vss | P4 | Vssa |
| B2 | DAT3 | E7 | Vss | K9 | Vcc | P5 | Vcca |
| B3 | DAT4 | F5 | Vcc | M4 | Vcca | P6 | Vssa |
| B4 | DAT5 | G5 | Vss | M5 | CMD | -- | -- |
| B5 | DAT6 | H5 | DS | M6 | CLK | -- | -- |
| B6 | DAT7 | H10 | Vss | N2 | Vssa | -- | -- |

Note:

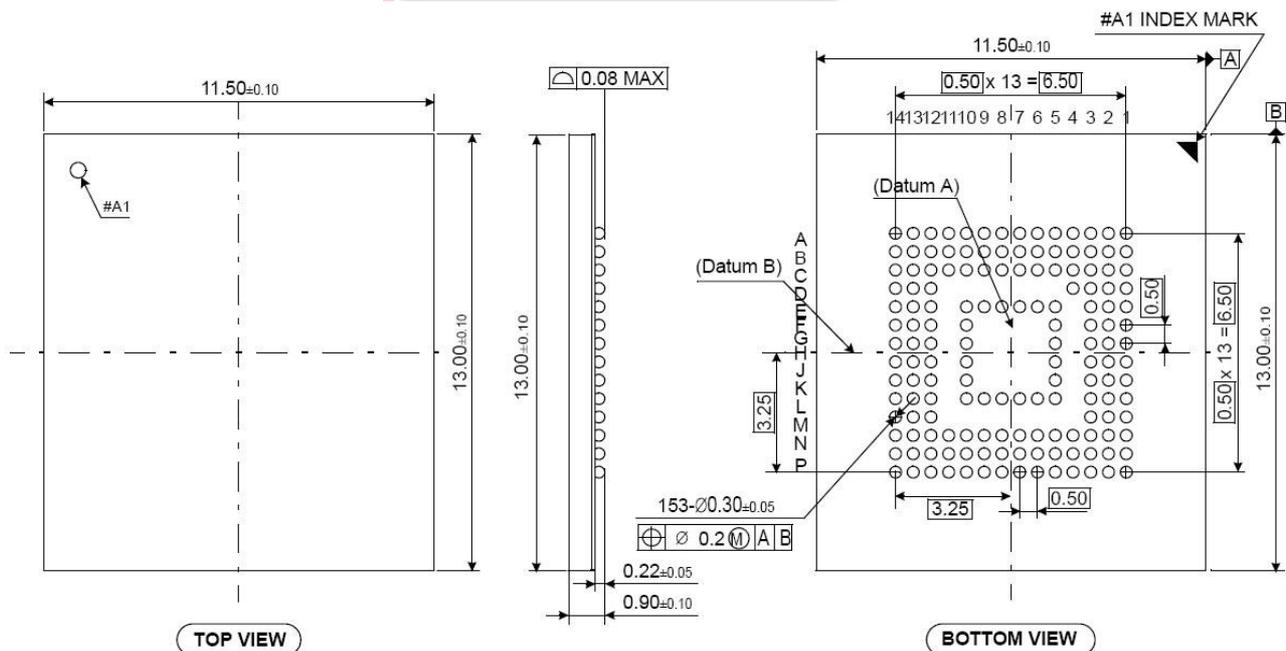
- NC:** No Connect, can be connected to ground or left floating.
- RFU:** Reserved for Future Use, should be left floating for future use.
- VSF:** Vendor Specific Function, shall be left floating.

2.2 Ball Assignment

| Signal | Ball No. | Description |
|-----------------------------------|--|--|
| CLOCK (CLK) | M6 | Each cycle of the clock directs a transfer on the command line and on the data lines. |
| COMMAND (CMD) | M5 | This signal is a bidirectional command channel used for device initialization and command transfer. The CMD Signal has 2 operation modes: open drain for initialization, and push-pull for fast command transfer. |
| DATA (DAT0-DAT7) | A3~A5 B2~B6 | These are bidirectional data channels. The DAT signals operate in push-pull mode. |
| RST_n | K5 | Hardware Reset Input |
| DS | H5 | Data Strobe: Return Clock signal used in HS400 mode |
| V _{CCQ} | C6,M4,N4,P3,P5 | Power supply for MMC interface and Controller, have two power mode: High power mode:2.7V~3.6V; Lower power mode:1.7V~1.95V |
| V _{CC} | E6,F5,J10,K9 | Power supply for NAND flash memory, its power voltage range is: 2.7V~3.6V |
| VDDi | C2 | VDDi is internal power mode. Connect 0.1uF or 2.2uF capacitor from VDDi to ground |
| V _{SS} ,V _{SSQ} | A6, E7, G5, H10, J5, K8, C4, N2, N5, P4, P6 | Ground lines |

Note: All other pins are not connected [NC] and can be connected to GND or left floating.

2.3 Package Dimensions

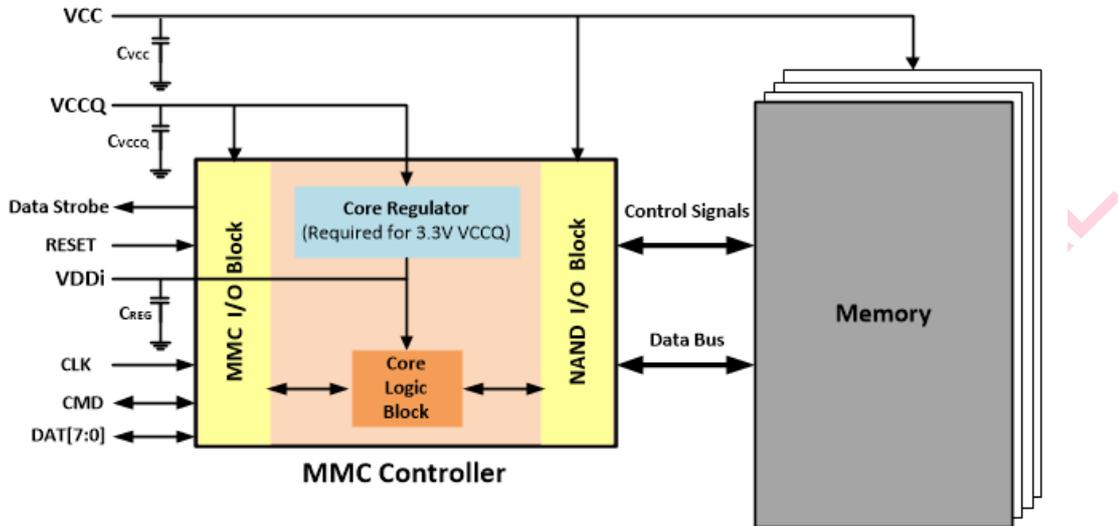


Unit: mm

11.5mmx13mmx1.0mm Package Dimensions

2.4 Product Architecture

e•MMC consists of NAND Flash and Controller. V_{CCQ} is for Controller power and V_{CC} is for flash power.



| Parameter | Symbol | Unit | Min. | Typ. | Max. |
|----------------------|------------|------|------|---------|------|
| VDDi capacitor value | C_{REG} | uF | 0.1 | 1.0+0.1 | 2.2 |
| VCC capacitor value | C_{VCC} | uF | - | 2.2+0.1 | - |
| VCCQ capacitor value | C_{VCCQ} | uF | - | 2.2+0.1 | - |

Note:

e•MMC recommends that the minimum value should be usually applied as the value of C_{REG} ; C_{REG} shall be compliant with X5R/X7R of EIA standard or B of JIS standard.

3 e•MMC Features

3.1 HS400 mode

■ The HS400 mode has the following features

- DDR Data sampling method
- CLK frequency up to 200 MHz DDR – up to 400 MB/s
- Only 8-bits bus width supported
- Signaling levels of 1.8 V
- Support up to 5 Drive Strengths
- Data strobe signal is toggled only for Data out, CRC response and CMD Response

■ I/O driver strength types

| Driver Type Values | Support | Nominal Impedance | Approximated driving capability compared to Type-0 | Remark |
|--------------------|-----------|-------------------|--|--|
| 0x0 | Mandatory | 50 Ω | x1 | Default Driver Type. Supports up to 200 MHz operation |
| 0x1 | Optional | 33 Ω | x1.5 | Supports up to 200 MHz operation. |
| 0x2 | Optional | 66 Ω | x0.75 | The weakest driver that supports up to 200 MHz operation. |
| 0x3 | Optional | 100 Ω | x0.5 | For low noise and low EMI systems. Maximal operating frequency is decided by Host design |
| 0x4 | Optional | 40 Ω | x1.2 | |

Note: Support of Driver Type-0 is mandatory for HS200 and HS400 device.

■ Device type values (EXT_CSD Register: DEVICE_TYPE [196])

| Bit | Device Type | Supportability |
|-----|--|----------------|
| 7 | HS400 Dual Data Rate e•MMC @ 200 MHz - 1.2V I/O | Not support |
| 6 | HS400 Dual Data Rate e•MMC @ 200 MHz - 1.8V I/O | Support |
| 5 | HS200 Single Data Rate e•MMC @ 200 MHz - 1.2V I/O | Not support |
| 4 | HS200 Single Data Rate e•MMC @ 200 MHz - 1.8V I/O | Support |
| 3 | High-Speed Dual Data Rate e•MMC @ 52MHz - 1.2V I/O | Not support |
| 2 | High-Speed Dual Data Rate e•MMC @ 52MHz - 1.8V or 3V I/O | Support |
| 1 | High-Speed e•MMC @ 52MHz - at rated device voltage(s) | Support |
| 0 | High-Speed e•MMC @ 26MHz - at rated device voltage(s) | Support |

Note: It is being discussed in JEDEC and is not confirmed yet. It can be modified according to JEDEC standard in the future.

■ Extended CSD revisions (EXT_CSD Register: EXT_CSD_REV [192])

| Value | Timing Interface | EXT_CSD Register Value |
|-------|------------------------------------|------------------------|
| 255–9 | Reserved | - |
| 8 | Revision 1.8 (for MMC v5.1) | 0x08 |
| 7 | Revision 1.7 (for MMC V5.0) | - |
| 6 | Revision 1.6 (for MMC V4.5, V4.51) | - |
| 5 | Revision 1.5 (for MMC V4.41) | - |

| | | |
|---|-----------------------------|---|
| 4 | Revision 1.4 (Obsolete) | - |
| 3 | Revision 1.3 (for MMC V4.3) | - |
| 2 | Revision 1.2 (for MMC V4.2) | - |
| 1 | Revision 1.1 (for MMC V4.1) | - |
| 0 | Revision 1.0 (for MMC V4.0) | - |

Note: Current e•MMC standard defined by JEDEC supports up to 0x08 for EXT_CSD_REV value.

■ **High Speed timing values (EXT_CSD Register: HS_TIMING [185])**

| Value | Timing Interface | Supportability |
|-------|--|----------------|
| 0x0 | Selecting backwards compatibility interface timing | Support |
| 0x1 | High Speed | Support |
| 0x2 | HS200 | Support |
| 0x3 | HS400 | Support |

4 e•MMC 5.1 Features

4.1 Overview

| New Feature | JEDEC | Support |
|------------------------------|-----------|---------|
| Cache Flushing Report | Mandatory | Yes |
| Background operation control | Mandatory | Yes |
| Command Queuing | Optional | Yes |
| Enhanced Strobe | Optional | Yes |
| RPMB Throughput improve | Optional | Yes |

4.2 Command Queuing

To facilitate command queuing in eMMC, the device manages an internal task queue that the host can queue during data transfer tasks.

Every task is issued by the host and initially queued as pending. The device works to prepare pending tasks for execution. When a task is ready for execution, its state changes to “ready for execution”.

The host tracks the state of all queued tasks and may order the execution of any task, marked as “ready for execution”, by sending a command indicating its task ID. The device executes the data transfer transaction after receiving the execute command (CMD46/CMD47).

4.2.1 CMD Set Description

■ CMD Set Description and Details

| CMD | Type | Argument | Abbreviation | Purpose |
|-------|---------|---|---------------------|--|
| CMD44 | ac/R1 | [31] Reliable Write Request [30] DAT_DIR - "0" write / "1" read [29] tag request [28:25] context ID [24] forced programming [23] Priority: "0" simple / "1" high [20:16] TASK ID [15:0] number of blocks | QUEUED_TASK_PARAMS | Define direction of operation (Read or Write) and Set high priority CMD Queue with task ID |
| CMD45 | ac/R1 | [31:0] Start block address | QUEUED_TASK_ADDRESS | Indicate data address for Queued CMD |
| CMD46 | adtc/R1 | [20:16] TASK ID | EXECUTE_READ_TASK | (Read) Transmit the requested number of data blocks |
| CMD47 | adtc/R1 | [20:16] TASK ID | EXECUTE_WRITE_TASK | (Write) Transmit the requested number of data blocks |
| CMD48 | ac/R1b | [20:16] Task ID [3:0] TM op-code | CMDQ_TASK_MGMT | Reset a specific task or entire queue. [20:16] when TM op-code = 2h these bits represent TaskID. When TM op-code = 1h these bits are reserved." |

4.2.2 New Response: QSR (Queue Status Register)

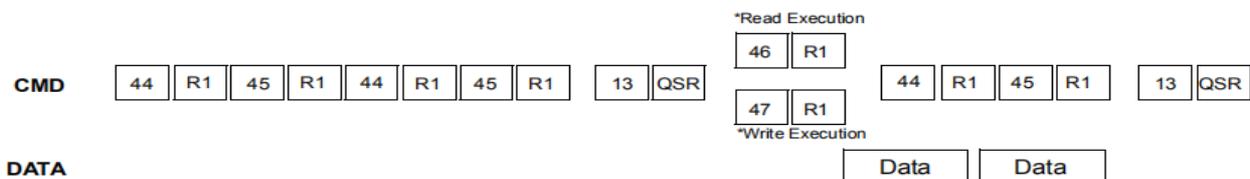
The 32-bit Queue Status Register (QSR) carries the state of tasks in the queue at a specific point in time. The host has read access to this register through device response to SEND_STATUS command (CMD13 with bit[15]="1"), R1's argument will be the 32-bit Queue Status Register (QSR). Every bit in the QSR represents the task whose ID corresponds to the bit index. If bit QSR[i] = "0", then the queued task with a Task ID i is not ready for execution. The task may be queued and pending, or the Task ID is unused. If bit QSR[i] = "1", then the queued task with Task ID i is ready for execution.

4.2.3 Send Status: CMD13

CMD13 for reading the Queue Status Register (QSR) by the host. If bit[15] in CMD13's argument is set to 1, then the device shall send an R1 Response with the QSR instead of the Device Status. * There is still legacy CMD13 with R` response.

4.2.4 Mechanism of CMD Queue operation

Host issues CMD44 with Task ID number, Sector, Count, Direction, Priority to the device followed by CMD45 and host checks the Queue Status check with CMD13 [15]bits to 1. After that host issues CMD46 for Read or CMD47 for write During CMD queue operation, CMD44/CMD45 is able to be issued at anytime when the CMD line is not in use



4.2.5 CMD Queue Register description

Configuration and capability structures shall be added to the EXT_CSD register, as described below

■ CMD Queuing Support (EXT_CSD register : CMDQ_SUPPORT [308])

| Bit7 | Bit6 | Bit5 | Bit4 | Bit3 | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|------|------|------|--------------------------|
| Reserved | | | | | | | CMD Queue supportability |

This field indicates whether the device supports command queuing or not

0x0: CMD Queue function is not supported

0x1: CMD Queue function is supported

■ Command Queue Mode Enable(EXT_CSD register : CMDQ_MODE_EN [15])

| Bit7 | Bit6 | Bit5 | Bit4 | Bit3 | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|------|------|------|--------------------------|
| Reserved | | | | | | | CMD Queue supportability |

This field is used by the host enable command queuing

0x0: Queue function is not enabled

0x1: Queue function is enabled

■ CMD Queuing Depth(EXT_CSD register : CMDQ_DEPTH [307])

| Bit7 | Bit6 | Bit5 | Bit4 | Bit3 | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|------|------|------|--------------------------|
| Reserved | | | | | | | CMD Queue supportability |

This field is used to calculate the depth of the queue supported by the device

Bit encoding:

[7:5]: Reserved

[4:0]: N,a parameter used to calculate the Queue Depth of task queue in the device.

Queue Depth = N+1.

4.3 Enhanced Strobe Mode

This product supports Enhanced Strobe in HS400 mode and refer to the details as described in eMMC5.1 JEDEC standard.

4.4 RPMB Throughput improve

[Table 11] Related parameter register in EXT_CSD : WR_REL_PARAM [166]

| Name | Field | Bit | Type |
|------------------------------|----------------|-----|------|
| Enhanced RPMB Reliable Write | EN_RPMB_REL_WR | 4 | R |

Bit[4]: EN_RPMB_REL_WR(R)

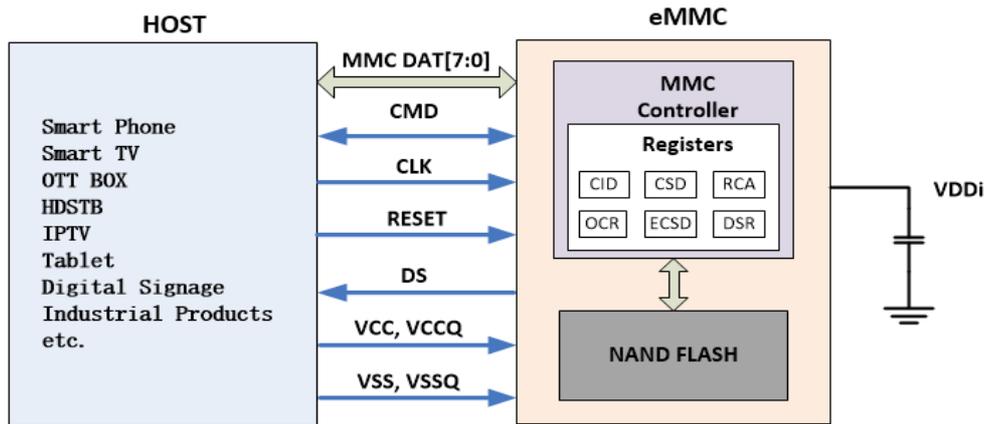
0x0: RPMB transfer size is either 256B (single 512B frame) or 512B (Two 512B frame).

0x1: RPMB transfer size is either 256B (single 512B frame), 512B (Two 512B frame), or 8KB(Thirthy two 512B frames).

5 Usage Overview

5.1 General Description

The e•MMC can be operated in 1, 4, or 8-bit mode. NAND flash memory is managed by a controller inside, which manages ECC, wear leveling and bad block management. e•MMC provides easy integration with the host process that all flash management hassles are invisible to the host.



5.2 Partition Management

The memory configuration initially consists (before any partitioning operation) of the User Data Area and RPMB Area Partitions and two Boot Area Partitions.

The embedded device also offers the host the possibility to configure additional local memory partitions with independent address spaces, starting from logical address 0x00000000, for different usage models.

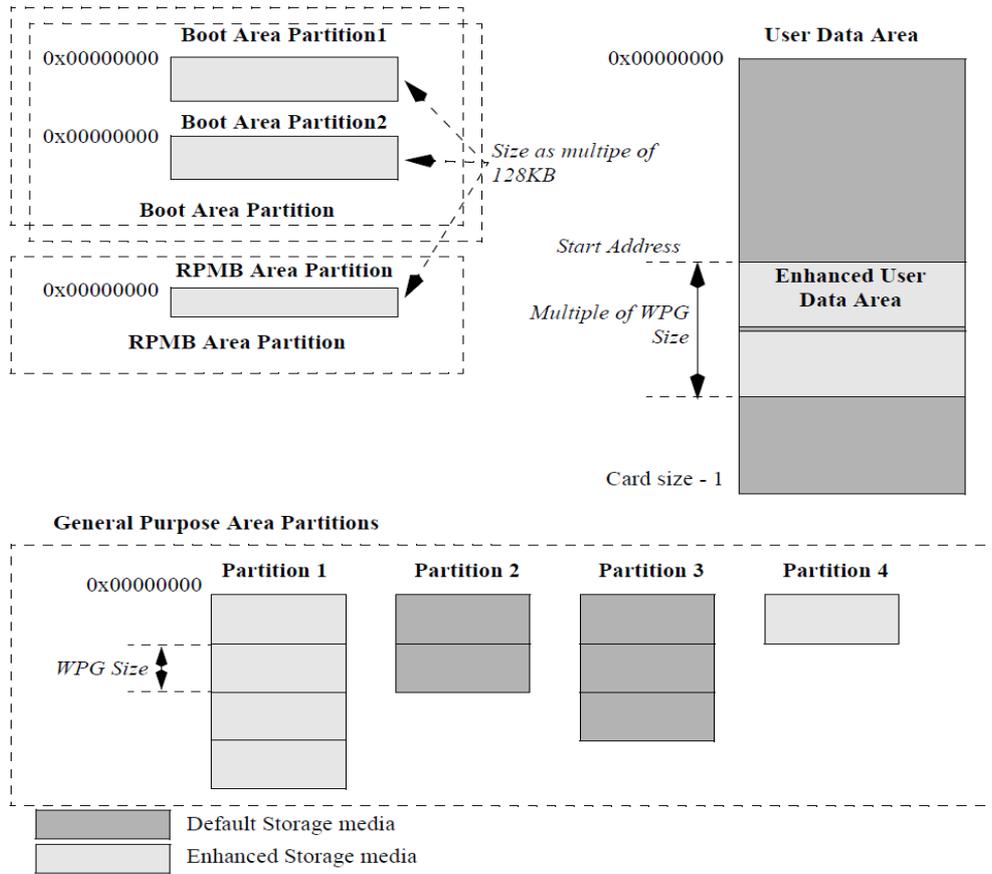
Therefore, the memory block areas can be classified as follows:

- Two Boot Area Partitions, whose size is multiple of 128 KB and where booting from e•MMC can be performed.
- One RPMB Partition accessed through a trusted mechanism, whose size is defined as multiple of 128 KB.
- Four General Purpose Area Partitions to store sensitive data or for other host usage models, whose sizes are a multiple of a Write Protect Group.

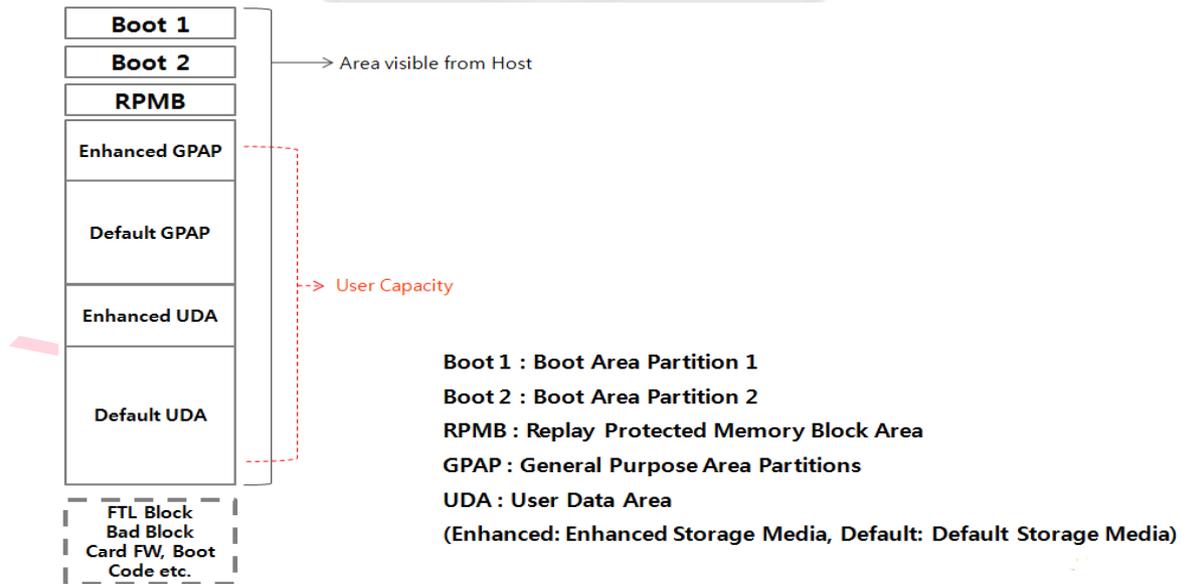
Boot and RPMB Area Partitions' sizes and attributes are defined by the memory manufacturer (read-only), while General Purpose Area Partitions' sizes and attributes can be programmed by the host only once in the device life-cycle (one-time programmable).

Moreover, the host is free to configure one segment in the User Data Area to be implemented as enhanced storage media, and to specify its starting location and size in terms of Write Protect Groups. The attributes of this Enhanced User Data Area can be programmed only once during the device life-cycle (one-time programmable).

A possible final configuration can be the following:



5.3 User Density



■ **Boot and RPMB Size**

| | Boot1 Size | Boot2 Size | RPMB Size |
|---------|------------|------------|-----------|
| Default | 4096 KB | 4096 KB | 4096 KB |
| Max. | 4096 KB | 4096 KB | 4096 KB |

■ **User Density Size**

| Capacity | User Area Capacity | SEC_COUNT in Extended CSD |
|----------|--------------------------------------|---------------------------|
| 64 GB | 62,537,072,640 Bytes (59640 MB) | 0x747C000 |
| 128 GB | 125,074,145,280 Bytes (119280 MB) | 0xE8F8000 |

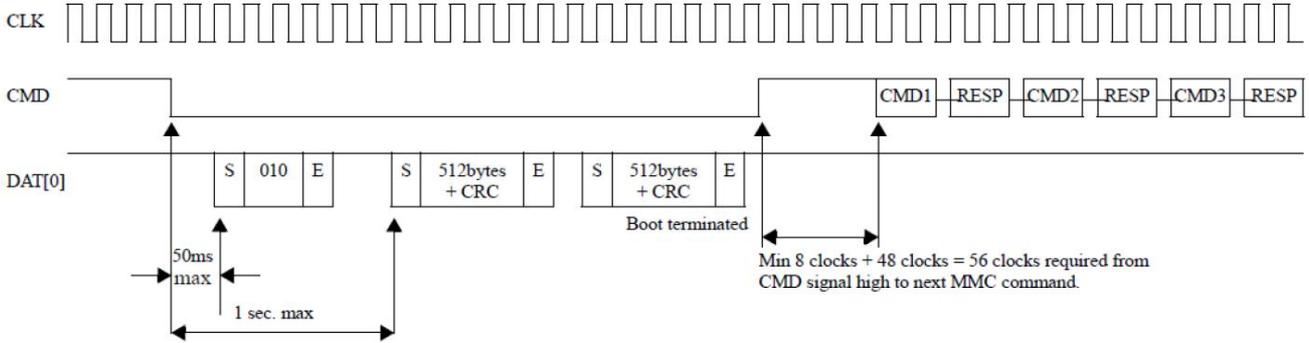
5.4 Performance

| Capacity | Part Number | Mode | Sequential Read (MB/s) | SLC Sequential Write (MB/s) | Sustained Sequential Write (MB/s) |
|----------|-----------------|-------|------------------------|-----------------------------|-----------------------------------|
| 64 GB | SGM8100C-S36BCG | HS400 | 280 | 180 | 30 |
| 128 GB | SGM8100C-S36BDG | HS400 | 280 | 200 | 60 |

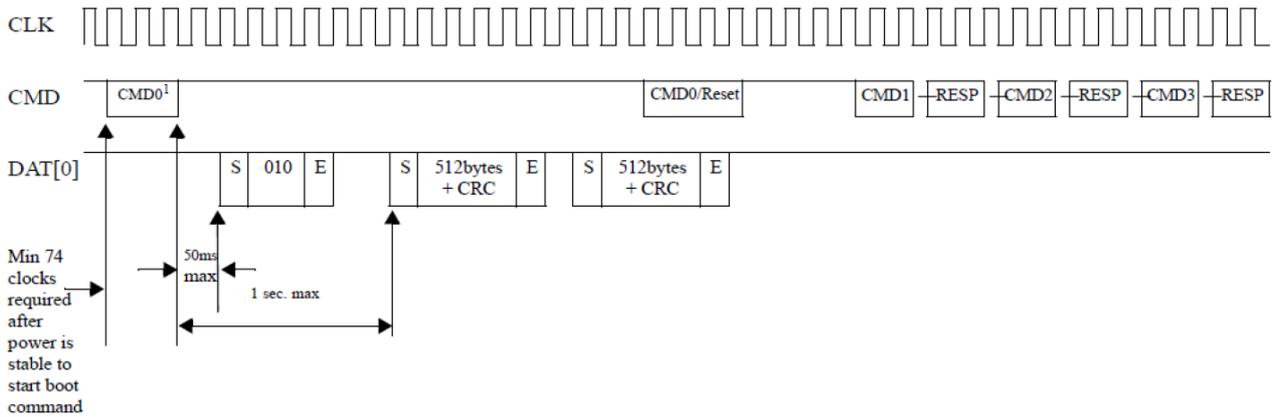
Test Condition: Bus width x8, 200MHz DDR, 512KB data transfer, w/o file system overhead, measured on internal board.

5.5 Boot Operation Mode

In boot operation mode, the master can read boot data from the slave (device) by keeping CMD line low or sending CMD0 with argument + 0xFFFFFFFF, before issuing CMD1. The data can be read from either boot area or user area depending on register setting.



State diagram (boot mode)
Boot operation complete Clock = 400 kHz
(Compatible with the description which ≤400kHz)



NOTE 1. CMD0 with argument 0xFFFFFFFF

State diagram (alternative boot mode)

6 Device Register

6.1 OCR Register

The 32-bit operation conditions register (OCR) stores the V_{DD} voltage profile of the Device and the access mode indication. In addition, this register includes a status information bit. This status bit is set if the Device power up procedure has been finished. The OCR register shall be implemented by all Devices.

| OCR bit | V_{CCQ} voltage window | e•MMC |
|---------|----------------------------------|--------------------------------------|
| [6:0] | Reserved | 000 0000b |
| [7] | 1.7–1.95 | 1b |
| [14:8] | 2.0–2.6 | 000 0000b |
| [23:15] | 2.7–3.6 | 1 1111 1111b |
| [28:24] | Reserved | 000 0000b |
| [30:29] | Access Mode | 00b (byte mode) 10b (sector mode) |
| [31] | Card power up status bit (busy)* | |

Note*: This bit is set to LOW if the e•MMC has not finished the power up routine. The supported voltage range is coded as shown in table.

6.2 CID Register

The Device IDentification (CID) register is 128 bits wide. It contains the Device identification information used during the Device identification phase (e•MMC protocol). Every individual flash or I/O Device shall have a unique identification number. Every type of e•MMC Device shall have a unique identification number. Table 75 lists these identifiers. The structure of the CID register is defined in this section.

| Name | Field | Width | CID-slice | CID Value |
|-----------------------|-------|-------|-----------|---------------------------------|
| Manufacturer ID | MID | 8 | [127:120] | 0xEA |
| Reserved | - | 6 | [119:114] | 0x0 |
| Card/BGA | CBX | 2 | [113:112] | 0x1 |
| OEM/Application ID | OID | 8 | [111:104] | 0x0E |
| Product name | PNM | 48 | [103:56] | 0x53 50 65 4D 4D 43 (SPeMMC) |
| Product revision | PRV | 8 | [55:48] | 0x10 |
| Product serial number | PSN | 32 | [47:16] | Serial number |
| Manufacturing date | MDT | 8 | [15:8] | Manufacturing date |
| CRC7 checksum | CRC | 7 | [7:1] | CRC7 |
| Not used, always '1' | - | 1 | [0:0] | 0x1 |

6.3 CSD Register

The Card-Specific Data register provides information on how to access the e•MMC contents. The CSD defines the data format, error correction type, maximum data access time, data transfer speed, whether the DSR register can be used etc. The programmable part of the register (entries marked by W or E, see below) can be changed by CMD27. The type of the entries in the table below is coded as follows:

R: Read only

- W: One time programmable and not readable.
- R/W: One time programmable and readable.
- W/E: Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and not readable.
- R/W/E: Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and readable.
- R/W/C_P: Writable after value cleared by power failure and HW/ rest assertion (the value not cleared by CMD0 reset) and readable.
- R/W/E_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and readable.
- W/E_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and not readable.

| Name | Field | Width | Cell Type | CSD-slice | Value |
|--|--------------------|-------|-----------|-----------|-------|
| CSD structure | CSD_STRUCTURE | 2 | R | [127:126] | 0x3 |
| System specification version | SPEC_VERS | 4 | R | [125:122] | 0x4 |
| Reserved | - | 2 | R | [121:120] | 0x0 |
| Data read access-time 1 | TAAC | 8 | R | [119:112] | 0x4F |
| Data read access-time 2 in CLK cycles (NSAC*100) | NSAC | 8 | R | [111:104] | 0x1 |
| Max. bus clock frequency | TRAN_SPEED | 8 | R | [103:96] | 0x32 |
| Card command classes | CCC | 12 | R | [95:84] | 0xF5 |
| Max. read data block length | READ_BL_LEN | 4 | R | [83:80] | 0x9 |
| Partial blocks for read allowed | READ_BL_PARTIAL | 1 | R | [79:79] | 0x0 |
| Write block misalignment | WRITE_BLK_MISALIGN | 1 | R | [78:78] | 0x0 |
| Read block misalignment | READ_BLK_MISALIGN | 1 | R | [77:77] | 0x0 |
| DSR implemented | DSR_IMP | 1 | R | [76:76] | 0x0 |
| Reserved | - | 2 | R | [75:74] | 0x0 |
| Device size | C_SIZE | 12 | R | [73:62] | 0xFFF |
| Max. read current @ VDD min | VDD_R_CURR_MIN | 3 | R | [61:59] | 0x6 |
| Max. read current @ VDD max | VDD_R_CURR_MAX | 3 | R | [58:56] | 0x6 |
| Max. write current @ VDD min | VDD_W_CURR_MIN | 3 | R | [55:53] | 0x6 |
| Max. write current @ VDD max | VDD_W_CURR_MAX | 3 | R | [52:50] | 0x6 |
| Device size multiplier | C_SIZE_MULT | 3 | R | [49:47] | 0x7 |
| Erase group size | ERASE_GRP_SIZE | 5 | R | [46:42] | 0x1F |
| Erase group size multiplier | ERASE_GRP_MULT | 5 | R | [41:37] | 0x1F |
| Write protect group size | WP_GRP_SIZE | 5 | R | [36:32] | 0xF |
| Write protect group enable | WP_GRP_MULT | 1 | R | [31:31] | 0x1 |
| Manufacturer default | ECC_DEFAULT_ECC | 2 | R | [30:29] | 0x0 |
| Write speed factor | R2W_FACTOR | 3 | R | [28:26] | 0x5 |
| Max. write data block length | WRITE_BL_LEN | 4 | R | [25:22] | 0x9 |
| Partial blocks for write allowed | WRITE_BL_PARTIAL | 1 | R | [21:21] | 0x0 |
| Reserved | - | 4 | R | [20:17] | 0x0 |
| Content protection application | CONTENT_PROT_APP | 1 | R | [16:16] | 0x0 |
| File format group | FILE_FORMAT_GRP | 1 | R/W | [15:15] | 0x0 |
| Copy flag(OTP) | COPY | 1 | R/W | [14:14] | 0x0 |
| Permanent write protection | PERM_WRITE_PROTECT | 1 | R/W | [13:13] | 0x0 |
| Temporary write protection | TMP_WRITE_PROTECT | 1 | R/W/E | [12:12] | 0x0 |
| File format | FILE_FORMAT | 2 | R/W | [11:10] | 0x0 |
| ECC code | ECC | 2 | R/W/E | [9:8] | 0x0 |
| CRC | CRC | 7 | R/W/E | [7:1] | 0x0 |
| Not used, always '1' | - | 1 | - | [0:0] | 0x1 |

6.4 Extended CSD Register

The Extended CSD register defines the e•MMC properties and selected modes. It is 512 bytes long.

The most significant 320 bytes are the Properties segment, which defines the e•MMC capabilities and cannot be modified by the host. The lower 192 bytes are the Modes segment, which defines the configuration the e•MMC is working in. These modes can be changed by the host by means of the SWITCH command.

R: Read only

W: One time programmable and not readable.

R/W: One time programmable and readable.

W/E: Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and not readable.

R/W/E: Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and readable.

R/W/C_P: Writable after value cleared by power failure and HW/ rest assertion (the value not cleared by CMD0 reset) and readable.

R/W/E_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and readable.

W/E/_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and not readable.

| Name | Field | Size (Bytes) | Cell Type | CSD-slice | Value |
|---|---|--------------|-----------|-----------|---------|
| Properties Segment | | | | | |
| Reserved | - | 6 | TBD | [511:506] | All "0" |
| Extended Security Commands Error | EXT_SECURITY_ERR | 1 | R | [505] | 0x0 |
| Supported Command Sets | S_CMD_SET | 1 | R | [504] | 0x1 |
| HPI features | HPI_FEATURES | 1 | R | [503] | 0x1 |
| Background operations support | BKOPS_SUPPORT | 1 | R | [502] | 0x1 |
| Max packed read commands | MAX_PACKED_READS | 1 | R | [501] | 0x3F |
| Max packed write commands | MAX_PACKED_WRITES | 1 | R | [500] | 0x3F |
| Data Tag Support | DATA_TAG_SUPPORT | 1 | R | [499] | 0x1 |
| Tag Unit Size | TAG_UNIT_SIZE | 1 | R | [498] | 0x5 |
| Tag Resources Size | TAG_RES_SIZE | 1 | R | [497] | 0x1 |
| Context management capabilities | CONTEXT_CAPABILITIES | 1 | R | [496] | 0x5 |
| Large Unit size | LARGE_UNIT_SIZE_M1 | 1 | R | [495] | 0x1 |
| Extended partitions attribute support | EXT_SUPPORT | 1 | R | [494] | 0x3 |
| Supported modes | SUPPORTED_MODES | 1 | R | [493] | 0x1 |
| FFU features | FFU_FEATURES | 1 | R | [492] | 0x1 |
| Operation codes timeout | OPERATION_CODE_TIMEOUT | 1 | R | [491] | 0xD |
| FFU Argument | FFU_ARG | 4 | R | [490:487] | 0x0 |
| Barrier support | BARRIER_SUPPORT | 1 | R | [486] | 0x1 |
| Reserved | - | 177 | TBD | [485:309] | All "0" |
| CMD Queuing Support | CMDQ_SUPPORT | 1 | R | [308] | 0x1 |
| CMD Queuing Depth | CMDQ_DEPTH | 1 | R | [307] | 0x1F |
| Reserved | - | 1 | TBD | [306] | 0x0 |
| Number of FW sectors correctly programmed | NUMBER_OF_FW_SECTORS_CORRECTLY_PROGRAMMED | 4 | R | [305:302] | 0x0 |
| Vendor proprietary health report | VENDOR_PROPRIETARY_HEALTH_REPORT | 32 | R | [301:270] | All "0" |
| Device life time estimation type B | DEVICE_LIFE_TIME_EST_TYP_B | 1 | R | [269] | 0x1 |
| Device life time estimation type A | DEVICE_LIFE_TIME_EST_TYP_A | 1 | R | [268] | 0x1 |

| Name | Field | Size (Bytes) | Cell Type | CSD-slice | Value |
|---|--|--------------|-----------|-----------|------------------------------------|
| Pre EOL information | PRE_EOL_INFO | 1 | R | [267] | 0x1 |
| Optimal read size | OPTIMAL_READ_SIZE | 1 | R | [266] | 0x40 |
| Optimal write size | OPTIMAL_WRITE_SIZE | 1 | R | [265] | 0x40 |
| Optimal trim unit size | OPTIMAL_TRIM_UNIT_SIZE | 1 | R | [264] | 0x7 |
| Device version | DEVICE_VERSION | 2 | R | [263:262] | 0x0 |
| Firmware version | FIRMWARE_VERSION | 8 | R | [261:254] | FW version |
| Power class for 200MHz, DDR at V _{CC} = 3.6V | PWR_CL_DDR_200_360 | 1 | R | [253] | 0x0 |
| Cache size | CACHE_SIZE | 4 | R | [252:249] | 0x300 |
| Generic CMD6 timeout | GENERIC_CMD6_TIME | 1 | R | [248] | 0x14 |
| Power off notification(long) timeout | POWER_OFF_LONG_TIME | 1 | R | [247] | 0x64 |
| Background operations status | BKOPS_STATUS | 1 | R | [246] | 0x0 |
| Number of correctly programmed sectors | CORRECTLY_PRG_SECTORS_NUM | 4 | R | [245:242] | 0x0 |
| 1st initialization time after partitioning | INI_TIMEOUT_AP | 1 | R | [241] | 0xA |
| Cache Flushing Policy | CACHE_FLUSH_POLICY | 1 | R | [240] | 0x1 |
| Power class for 52MHz, DDR at V _{CC} = 3.6V | PWR_CL_DDR_52_360 | 1 | R | [239] | 0x0 |
| Power class for 52MHz, DDR at V _{CC} = 1.95V | PWR_CL_DDR_52_195 | 1 | R | [238] | 0x0 |
| Power class for 200MHz at V _{CCQ} =1.95V, V _{CC} = 3.6V | PWR_CL_200_195 | 1 | R | [237] | 0x0 |
| Power class for 200MHz, at V _{CCQ} =1.3V, V _{CC} = 3.6V | PWR_CL_200_130 | 1 | R | [236] | 0x0 |
| Minimum Write Performance for 8bit at 52MHz in DDR mode | MIN_PERF_DDR_W_8_52 | 1 | R | [235] | 0x0 |
| Minimum Read Performance for 8bit at 52MHz in DDR mode | MIN_PERF_DDR_R_8_52 | 1 | R | [234] | 0x0 |
| Reserved | | 1 | TBD | [233] | 0x0 |
| TRIM Multiplier | TRIM_MULT | 1 | R | [232] | 0x2 |
| Secure Feature support | SEC_FEATURE_SUPPORT | 1 | R | [231] | 0x55 |
| Secure Erase Multiplier | SEC_ERASE_MULT | 1 | R | [230] | 0x1Bh |
| Secure TRIM Multiplier | SEC_TRIM_MULT | 1 | R | [229] | 0x11 |
| Boot information | BOOT_INFO | 1 | R | [228] | 0x7 |
| Reserved | | 1 | TBD | [227] | 0x0 |
| Boot partition size | BOOT_SIZE_MULT | 1 | R | [226] | 0x20 |
| Access size | ACC_SIZE | 1 | R | [225] | 0x6 |
| High-capacity erase unit size | HC_ERASE_GRP_SIZE | 1 | R | [224] | 0x1 |
| High-capacity erase timeout | ERASE_TIMEOUT_MULT | 1 | R | [223] | 0x1 |
| Reliable write sector count | REL_WR_SEC_C | 1 | R | [222] | 0x1 |
| High-capacity write protect group size | HC_WP_GRP_SIZE | 1 | R | [221] | 0x10 |
| Sleep current [V _{CC}] | S_C_VCC | 1 | R | [220] | 0xD |
| Sleep current [V _{CCQ}] | S_C_VCCQ | 1 | R | [219] | 0xD |
| Production state awareness timeout | PRODUCTION_STATE_AWARENES S_TIMEOUT | 1 | R | [218] | 0x6 |
| Sleep/awake timeout | S_A_TIMEOUT | 1 | R | [217] | 0x17 |
| Sleep Notification Timout1 | SLEEP_NOTIFICATION_TIME | 1 | R | [216] | 0xA |
| Sector Count | SEC_COUNT | 4 | R | [215:212] | 64GB: 0x747C000 128GB:0xE8F8000 |

| Name | Field | Size (Bytes) | Cell Type | CSD-slice | Value |
|--|-----------------------|--------------|-----------------|-----------|-------|
| Secure Write Protect Information | SECURE_WP_INFO | 1 | R | [211] | 0x0 |
| Minimum Write Performance for 8bit at 52MHz | MIN_PERF_W_8_52 | 1 | R | [210] | 0x0 |
| Minimum Read Performance for 8bit at 52MHz | MIN_PERF_R_8_52 | 1 | R | [209] | 0x0 |
| Minimum Write Performance for 8bit at 26MHz, for 4bit at 52MHz | MIN_PERF_W_8_26_4_52 | 1 | R | [208] | 0x0 |
| Minimum Read Performance for 8bit at 26MHz, for 4bit at 52MHz | MIN_PERF_R_8_26_4_52 | 1 | R | [207] | 0x0 |
| Minimum Write Performance for 4bit at 26MHz | MIN_PERF_W_4_26 | 1 | R | [206] | 0x0 |
| Minimum Read Performance for 4bit at 26MHz | MIN_PERF_R_4_26 | 1 | R | [205] | 0x0 |
| Reserved | | 1 | TBD | [204] | 0x0 |
| Power class for 26MHz at 3.6 V 1 R | PWR_CL_26_360 | 1 | R | [203] | 0x0 |
| Power class for 52MHz at 3.6 V 1 R | PWR_CL_52_360 | 1 | R | [202] | 0x0 |
| Power class for 26MHz at 1.95 V 1 R | PWR_CL_26_195 | 1 | R | [201] | 0x0 |
| Power class for 52MHz at 1.95 V 1 R | PWR_CL_52_195 | 1 | R | [200] | 0x0 |
| Partition switching timing | PARTITION_SWITCH_TIME | 1 | R | [199] | 0x6 |
| Out-of-interrupt busy timing | OUT_OF_INTERRUPT_TIME | 1 | R | [198] | 0xA |
| I/O Driver Strength | DRIVER_STRENGTH | 1 | R | [197] | 0x1 |
| Device type | DEVICE_TYPE | 1 | R | [196] | 0x57 |
| Reserved | | 1 | TBD | [195] | 0x0 |
| CSD Structure Version | CSD_STRUCTURE | 1 | R | [194] | 0x2 |
| Reserved | | 1 | TBD | [193] | 0x0 |
| Extended CSD Revision | EXT_CSD_REV | 1 | R | [192] | 0x8 |
| Modes Segment | | | | | |
| Command Set | CMD_SET | 1 | R/W/E_P | [191] | 0x0 |
| Reserved | | 1 | TBD | [190] | 0x0 |
| Command set revision | CMD_SET_REV | | R | [189] | 0x0 |
| Reserved | | 1 | TBD | [188] | 0x0 |
| Power class | POWER_CLASS | | R/W/E_P | [187] | 0x0 |
| Reserved | | 1 | TBD | [186] | 0x0 |
| High Speed Interface Timing | HS_TIMING | 1 | R/W/E_P | [185] | 0x0 |
| Strobe Support | STROBE_SUPPORT | 1 | R | [184] | 0x1 |
| Bus Width Mode | BUS_WIDTH | 1 | W/E_P | [183] | 0x0 |
| Reserved | | 1 | TBD | [182] | 0x0 |
| Erased memory range | ERASE_MEM_CONT | 1 | R | [181] | 0x0 |
| Reserved | | 1 | TBD | [180] | 0x0 |
| Partition Configuration | PARTITION_CONFIG | 1 | R/W/E & R/W/E_P | [179] | 0x0 |
| Boot Config protection | BOOT_CONFIG_PROT | 1 | R/W & R/W/C_P | [178] | 0x0 |
| Boot bus Conditions | BOOT_BUS_CONDITIONS | 1 | R/W/E | [177] | 0x0 |
| Reserved | | 1 | TBD | [176] | 0x0 |

| Name | Field | Size (Bytes) | Cell Type | CSD-slice | Value |
|--|-----------------------------|--------------|----------------------|-----------|-----------------------------|
| High-density erase group definition | ERASE_GROUP_DEF | 1 | R/W/E | [175] | 0x0 |
| Boot write protection status registers | BOOT_WP_STATUS | 1 | R | [174] | 0x0 |
| Boot area write protect register | BOOT_WP | 1 | R/W &R/W/C_P | [173] | 0x0 |
| Reserved | | 1 | TBD | [172] | 0x0 |
| User area write protect register | USER_WP | 1 | R/W,R/W/C_P &R/W/E_P | [171] | 0x0 |
| Reserved | | 1 | TBD | [170] | 0x0 |
| FW configuration | FW_CONFIG | 1 | R/W | [169] | 0x0 |
| RPMB Size | RPMB_SIZE_MULT | 1 | R | [168] | 0x20 |
| Write reliability setting register | WR_REL_SET | 1 | R/W | [167] | 0x1F |
| Write reliability parameter register | WR_REL_PARAM | 1 | R | [166] | 0x14 |
| Start Sanitize operation | SANITIZE_START | 1 | WE_P | [165] | 0x0 |
| Manually start background operations | BKOPS_START | 1 | WE_P | [164] | 0x0 |
| Enable background operations handshake | BKOPS_EN | 1 | R/W & R/W/E | [163] | 0x0 |
| H/W reset function | RST_n_FUNCTION | 1 | R/W | [162] | 0x0 |
| HPI management | HPI_MGMT | 1 | R/W/E_P | [161] | 0x0 |
| Partitioning Support | PARTITIONING_SUPPORT | 1 | R | [160] | 0x7 |
| Max Enhanced Area Size | MAX_ENH_SIZE_MULT | 3 | R | [159:157] | 64GB: 0x9B5 128GB:0x136A |
| Partitions attribute | PARTITIONS_ATTRIBUTE | 1 | R/W | [156] | 0x0 |
| Partitioning Setting | PARTITION_SETTING_COMPLETED | 1 | R/W | [155] | 0x0 |
| General Purpose Partition Size | GP_SIZE_MULT | 12 | R/W | [154:143] | 0x0 |
| Enhanced User Data Area Size | ENH_SIZE_MULT | 3 | R/W | [142:140] | 0x0 |
| Enhanced User Data Start Address | ENH_START_ADDR | 4 | R/W | [139:136] | 0x0 |
| Reserved | | 1 | TBD | [135] | 0x0 |
| Bad Block Management mode | SEC_BAD_BLK_MGMNT | 1 | R/W | [134] | 0x0 |
| Production state awareness | PRODUCTION_STATE_AWARENESS | 1 | R/W/E | [133] | 0x0 |
| Package Case Temperature is controlled | TCASE_SUPPORT | 1 | WE_P | [132] | 0x0 |
| Periodic Wake-up | PERIODIC_WAKEUP | 1 | R/W/E | [131] | 0x0 |
| Program CID/CSD in DDR mode support | PROGRAM_CID_CSD_DDR_SUPPORT | 1 | R | [130] | 0x0 |
| Reserved | | 2 | TBD | [129:128] | 0x0 |
| Vendor Specific Fields | NATIVE_SECTOR_SIZE | 1 | <vendor specific> | [127:64] | 0x0 |
| Native sector size | NATIVE_SECTOR_SIZE | 1 | R | [63] | 0x0 |
| Sector size emulation | USE_NATIVE_SECTOR | 1 | R/W | [62] | 0x0 |
| Sector size | DATA_SECTOR_SIZE | 1 | R | [61] | 0x0 |
| 1st initialization after disabling sector size emulation | INI_TIMEOUT_EMU | 1 | R | [60] | 0x0 |
| Class 6 commands control | CLASS_6_CTRL | 1 | R/W/E_P | [59] | 0x0 |
| Number of addressed group to be Released | DYNCAP_NEEDED | 1 | R | [58] | 0x0 |

| Name | Field | Size (Bytes) | Cell Type | CSD-slice | Value |
|------------------------------------|------------------------------------|--------------|-----------|-----------|-------------------------------------|
| Exception events control | EXCEPTION_EVENTS_CTRL | 2 | R/W/E_P | [57:56] | 0x0 |
| Exception events status | EXCEPTION_EVENTS_STATUS | 2 | R | [55:54] | 0x0 |
| Extended Partitions Attribute | EXT_PARTITIONS_ATTRIBUTE | 2 | R/W | [53:52] | 0x0 |
| Context configuration | CONTEXT_CONF | 15 | R/W/E_P | [51:37] | 0x0 |
| Packed command status | PACKED_COMMAND_STATUS | 1 | R | [36] | 0x0 |
| Packed command failure index | PACKED_FAILURE_INDEX | 1 | R | [35] | 0x0 |
| Power Off Notification | POWER_OFF_NOTIFICATION | 1 | R/W/E_P | [34] | 0x0 |
| Control to turn the Cache ON/OFF | CACHE_CTRL | 1 | R/W/E_P | [33] | 0x0 |
| Flushing of the cache | FLUSH_CACHE | 1 | WE_P | [32] | 0x0 |
| Control to turn the Barrier ON/OFF | BARRIER_CTRL | 1 | R/W | [31] | 0x0 |
| Mode config | MODE_CONFIG | 1 | R/W/E_P | [30] | 0x0 |
| Mode operation codes | MODE_OPERATION_CODES | 1 | WE_P | [29] | 0x0 |
| Reserved | | 2 | TBD | [28:27] | 0x0 |
| FFU status | FFU_STATUS | 1 | R | [26] | 0x0 |
| Pre loading data size | PRE_LOADING_DATA_SIZE | 4 | R/W/E_P | [25:22] | 0x0 |
| Max pre loading data size | MAX_PRE_LOADING_DATA_SIZE | 4 | R | [21:18] | 64GB: 0x1D1F000 128GB: 0x3A3E000 |
| Product state awareness enablement | PRODUCT_STATE_AWARENESS_ENABLEMENT | 1 | R/W/E & R | [17] | 0x3 |
| Secure Removal Type | SECURE_REMOVAL_TYPE | 1 | R/W & R | [16] | 0x1 |
| Command Queue Mode Enable | CMDQ_MODE_EN | 1 | R/W/E_P | [15] | 0x0 |
| Reserved | | 15 | TBD | [14:0] | 0x0 |

Note: Reserved bits should be read as “0”.

7 AC Parameter

7.1 Timing Parameter

■ Timing Parameter:

| Timing Parameter | | Max. Value | Unit |
|--|-------------------------|------------|------|
| Initialization Time (t _{INIT}) | Normal | 1 | s |
| | After partition setting | 3 | s |
| Read Timeout | | 150 | ms |
| Write Timeout | | 350 | ms |
| Erase Timeout | | 600 | ms |
| Force Erase Timeout | | 3 | min |
| Secure Erase Timeout | | 8 | s |
| Secure Trim step1 Timeout | | 5 | s |
| Secure Trim step2 Timeout | | 3 | s |
| Trim Timeout | | 300 | ms |
| Partition Switching Timeout (after Init) | | 30 | ms |
| Power Off Notification (Short) Timeout | | 100 | ms |
| Power Off Notification (Long) Timeout | | 600 | ms |

Note:

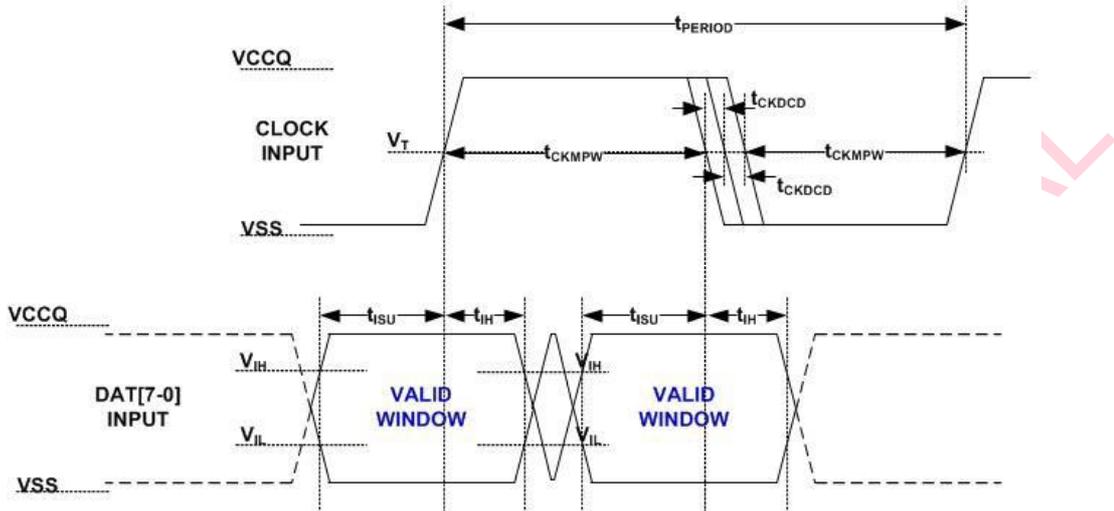
- Normal Initialization Time without partition setting
- Initialization Time after partition setting, refer to INI_TIMEOUT_AP in EXT_CSD register
- Be advised Timeout Values specified in Table above are for testing purposes under internal test pattern only and actual timeout situations may vary
- EXCEPTION_EVENT may occur and the actual timeout values may vary due to user environment

7.2 Bus Timing Parameters for DDR52 and HS200 are defined by JEDEC standard

7.3 Bus Timing Specification in HS400 mode

7.3.1 HS400 Device Input Timing

The CMD input timing for HS400 mode is the same as CMD input timing for HS200 mode.



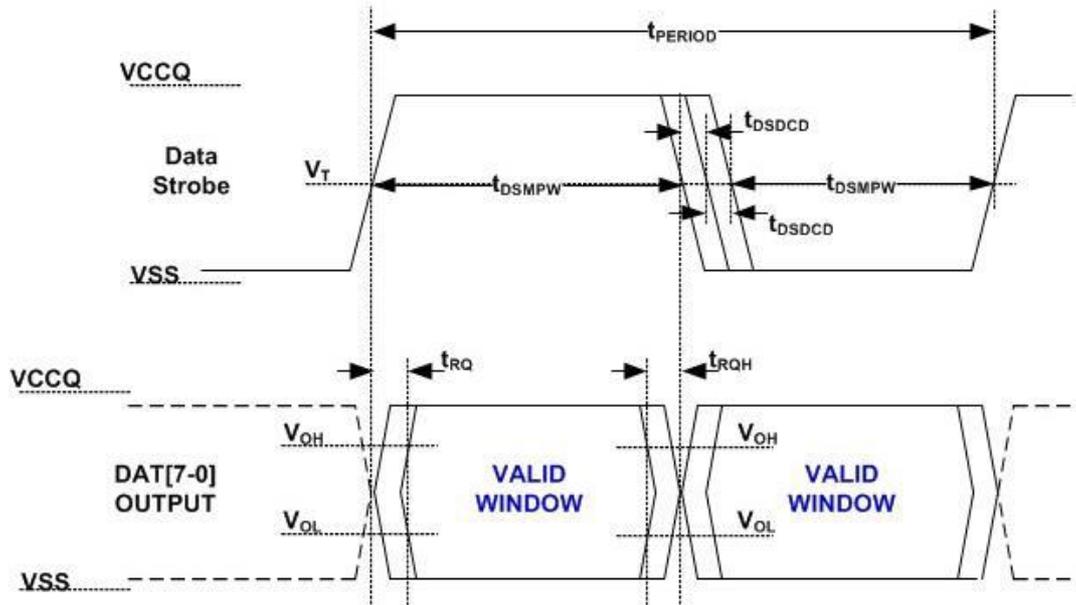
NOTE $V_T = 50\%$ of V_{CCQ} , indicates clock reference point for timing measurements.

■ HS400 Device Input Timing

| Parameter | Symbol | Min | Max | Unit | Remark |
|-------------------------------|--------------|-------|-----|------|--|
| Input CLK | | | | | |
| Cycle time data transfer mode | t_{PERIOD} | 5 | | | 200 MHz(max), between rising edges With respect to V_T . |
| Slew rate | SR | 1.125 | | V/ns | With respect to V_{IH}/V_{IL} . |
| Duty cycle distortion | t_{CKDCD} | 0.0 | 0.3 | ns | Allowable deviation from an ideal 50% duty cycle. With respect to V_T . Includes jitter, phase noise |
| Minimum pulse width | t_{CKMPW} | 2.2 | | ns | With respect to V_T . |
| Input DAT (referenced to CLK) | | | | | |
| Input set-up time | t_{ISUddr} | 0.4 | | ns | $C_{Device} \leq 6\text{ pF}$ With respect to V_{IH}/V_{IL} . |
| Input hold time | t_{IHddr} | 0.4 | | ns | $C_{Device} \leq 6\text{ pF}$ With respect to V_{IH}/V_{IL} . |
| Slew rate | SR | 1.125 | | V/ns | With respect to V_{IH}/V_{IL} . |

7.3.2 HS400 Device Output Timing

The Data Strobe is used to read data in HS400 mode. The Data Strobe is toggled only during data read or CRC status response.



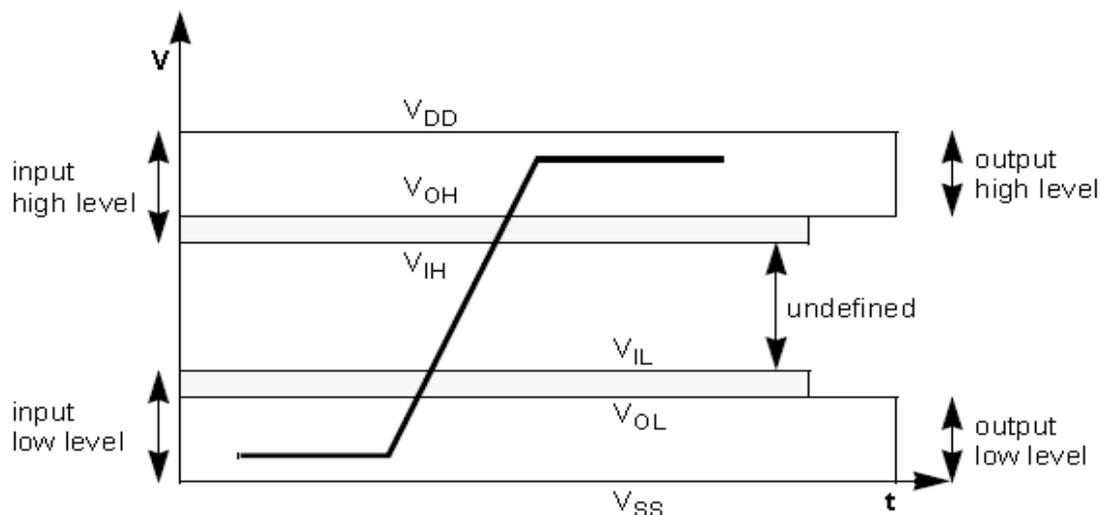
NOTE $V_T = 50\%$ of V_{CCQ} , indicates clock reference point for timing measurements.

■ HS400 Device Output Timing

| Parameter | Symbol | Min | Max | Unit | Remark |
|--|--------------|-------|-----|--------------|--|
| Data Strobe | | | | | |
| Cycle time data transfer mode | t_{PERIOD} | 5 | | | 200 MHz(max), between rising edges With respect to V_T . |
| Slew rate | SR | 1.125 | | V/ns | With respect to V_{OH}/V_{OL} and HS400 reference load |
| Duty cycle distortion | T_{DSDCD} | 0.0 | 0.2 | ns | Allowable deviation from the input CLK duty cycle distortion (t_{CKDCD}). With respect to V_T . Includes jitter, phase noise |
| Minimum pulse width | t_{DSMPW} | 2.0 | | ns | With respect to V_T . |
| Read pre-amble | t_{RPRE} | 0.4 | - | t_{PERIOD} | Max value is specified by manufacturer. Value up to infinite is valid |
| Read post-amble | t_{RPST} | 0.4 | - | t_{PERIOD} | Max value is specified by manufacturer. Value up to infinite is valid |
| Output DAT (referenced to Data Strobe) | | | | | |
| Output skew | t_{RQ} | | 0.4 | ns | With respect to V_{OH}/V_{OL} and HS400 reference load |
| Output hold skew | t_{RQH} | | 0.4 | ns | With respect to V_{OH}/V_{OL} and HS400 reference load |
| Slew rate | SR | 1.125 | | V/ns | With respect to V_{OH}/V_{OL} and HS400 reference load |

7.4 Bus Signal Levels

As the bus can be supplied with a variable supply voltage, all signal levels are related to the supply voltage.



7.4.1 Open-Drain Mode Bus Signal Level

| Parameter | Symbol | Min | Max | Unit | Conditions |
|---------------------|----------|-----------------|-----|------|----------------|
| Output HIGH voltage | V_{OH} | $V_{CCQ} - 0.2$ | | V | Note |
| Output LOW voltage | V_{OL} | | 0.3 | V | $I_{OL} = 2mA$ |

Note:

Because V_{oh} depends on external resistance value (including outside the package), this value does not apply as device specification. Host is responsible to choose the external pull-up and open drain resistance value to meet V_{oh} Min value.

7.4.2 Bus Signal Level (High-Voltage)

The device input and output voltages shall be within the following specified ranges for any V_{CCQ} of the allowed voltage range.

■ Push-pull signal level—high-voltage e•MMC

| Parameter | Symbol | Min | Max | Unit | Conditions |
|---------------------|----------|-------------------|-------------------|------|--|
| Output HIGH voltage | V_{OH} | $0.75 * V_{CCQ}$ | -- | V | $I_{OH} = -100\mu A @ V_{CCQ} \text{ min}$ |
| Output LOW voltage | V_{OL} | -- | $0.125 * V_{CCQ}$ | V | $I_{OL} = 100\mu A @ V_{CCQ} \text{ min}$ |
| Input HIGH voltage | V_{IH} | $0.625 * V_{CCQ}$ | $V_{CCQ} + 0.3$ | V | -- |
| Input LOW voltage | V_{IL} | $V_{SS} - 0.3$ | $0.25 * V_{CCQ}$ | V | -- |

■ Push-pull signal level—1.70 V -1.95 V V_{CCQ} voltage Range

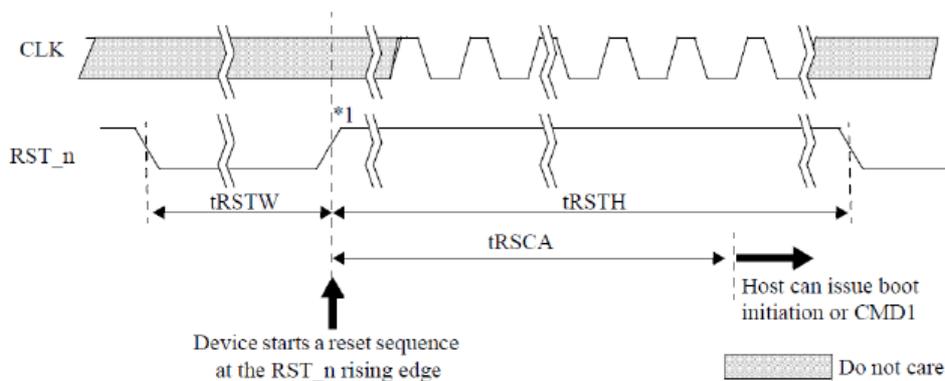
| Parameter | Symbol | Min | Max | Unit | Conditions |
|---------------------|-----------------|--------------------------------------|---------------------------|------|------------------------|
| Output HIGH voltage | V _{OH} | V _{CCQ} - 0.45 | -- | V | I _{OH} = -2mA |
| Output LOW voltage | V _{OL} | -- | 0.45 | V | I _{OL} = 2mA |
| Input HIGH voltage | V _{IH} | 0.65 * V _{CCQ} ¹ | V _{CCQ} + 0.3 | V | -- |
| Input LOW voltage | V _{IL} | V _{SS} - 0.3 | 0.35*V _{CCQ} (2) | V | -- |

Note:

- 0.7 * V_{DD} for MMC4.3 and older revisions.
- 0.3 * V_{DD} for MMC4.3 and older revisions.

7.5 H/W Reset Operation

■ H/W Reset waveform



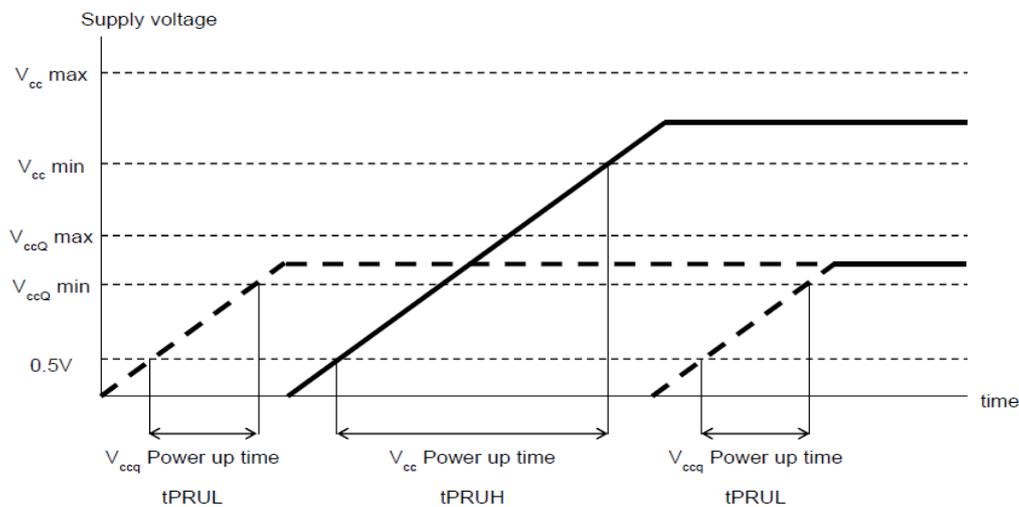
NOTE 1 Device will detect the rising edge of RST_n signal to trigger internal reset sequence.

■ H/W Reset Timing Parameters

| Symbol | Comment | Min | Max | Unit |
|-------------------|-----------------------------------|------------------|-----|------|
| t _{RSTW} | RST_n pulse width | 1 | | μs |
| t _{RSCA} | RST_n to Command time | 200 ¹ | | μs |
| t _{RSTH} | RST_n high period (interval time) | 1 | | μs |

Note 1: 74 cycles of clock signal required before issuing CMD1 or CMD0 with argument 0xFFFFFFFF.

7.6 Power-up sequence



Power-up parameter

| Parameter | Symbol | Test | Min | Max | Remark |
|--------------------------|-------------------|------|------|-------|--------|
| Supply power-up for 3.3V | t _{PRUH} | | 5 μs | 35 ms | -- |
| Supply power-up for 1.8V | t _{PRUL} | | 5 μs | 25 ms | -- |

8 DC Electrical Characteristics

8.1 Power Supply Voltage

| Parameter | Symbol | Test Conditions | Min | Max | Unit |
|-----------------------------|------------------|-----------------|-----|------|------|
| Supply voltage1 (NAND/Core) | V _{cc} | -- | 2.7 | 3.6 | V |
| Supply voltage 2 (CTRL/IO) | V _{ccq} | -- | 1.7 | 1.95 | V |
| | | | 2.7 | 3.6 | V |

8.2 Operating Current (RMS)

Active Power Consumption during operation

| Capacity | Operation | I _{cc} | I _{ccq} | Unit |
|----------|-----------|-----------------|------------------|------|
| | | (Max) | (Max) | |
| 64 GB | Read | 65 | 105 | mA |
| | Write | 85 | 100 | mA |
| 128 GB | Read | 65 | 105 | mA |
| | Write | 80 | 100 | mA |

Note:

- Power measurement conditions: Bus configuration =x8 @200MHz DDR
- Max RMS current is the average RMS current consumption over a period of 100ms.
- Temperature: 25°C
- V_{CC}=3.3V, V_{CCQ}=1.8V
- Not 100% tested

8.3 Standby Power Consumption

■ Standby Power Consumption in auto power saving mode and standby state

| Capacity | State | I _{CC} | | I _{CCQ} | | Unit |
|----------|---------|-----------------|------|------------------|------|------|
| | | 25°C | 85°C | 25°C | 85°C | |
| 64 GB | Standby | 0 | 0 | 150 | 600 | uA |
| 128 GB | | 0 | 0 | 150 | 600 | uA |

Note:

- Power measurement conditions: Bus configuration =x8, No CLK
- V_{CC}=3.3V, V_{CCQ}=1.8V
- Not 100% tested

8.4 Sleep Power Consumption

■ Sleep Power Consumption in Sleep State

| Capacity | State | I _{CC} | | I _{CCQ} | | Unit |
|----------|-------|-----------------|------|------------------|------|------|
| | | 25°C | 85°C | 25°C | 85°C | |
| 64 GB | Sleep | 0 | 0 | 150 | 600 | uA |
| 128 GB | | 0 | 0 | 150 | 600 | uA |

Note:

- Power measurement conditions: Bus configuration = x8, No CLK
- Enter sleep state by CMD5, V_{CC} power is switched off, V_{CCQ}=1.8V
- Not 100% tested

8.5 Bus Signal Line Load

The total capacitance C_L of each line of the e•MMC bus is the sum of the bus master capacitance C_{HOST} , the bus capacitance C_{BUS} itself and the capacitance C_{DEVICE} of the e•MMC connected to this line:

$$C_L = C_{HOST} + C_{BUS} + C_{DEVICE}$$

The sum of the host and bus capacitances should be under 20pF.

■ Bus Signal Line Load

| Parameter | Symbol | Min | Typ. | Max | Unit | Remark |
|---------------------------------------|--------------|-----|------|-----|------------|---------------------------------------|
| Pull-up resistance for CMD | R_{CMD} | 4.7 | -- | 100 | k Ω | to prevent bus floating |
| Pull-up resistance for DAT0–DAT7 | R_{DAT} | 10 | -- | 100 | k Ω | to prevent bus floating |
| Internal pull up resistance DAT1–DAT7 | R_{int} | 10 | -- | 150 | k Ω | to prevent unconnected lines floating |
| Bus signal line capacitance | C_L | -- | -- | 30 | pF | Single Device |
| Single Device capacitance | C_{DEVICE} | -- | -- | 12 | pF | Single Device capacitance |
| Maximum signal line inductance | -- | -- | -- | 16 | nH | $f_{pp} \leq 52$ MHz |

■ HS400 Capacitance and Resistors

| Parameter | Symbol | Min | Typ. | Max | Unit | Remark |
|--------------------------------------|--------------|-----|------|-----|------------|---------------|
| Pull-down resistance for Data Strobe | R_{DS} | 10 | -- | 100 | k Ω | |
| Single Device capacitance | C_{DEVICE} | | | 6 | pF | Single Device |
| Bus signal line capacitance | C_L | | | 13 | pF | Single Device |

Note: Recommended maximum value is 50 k Ω for 1.8V interface supply voltages.